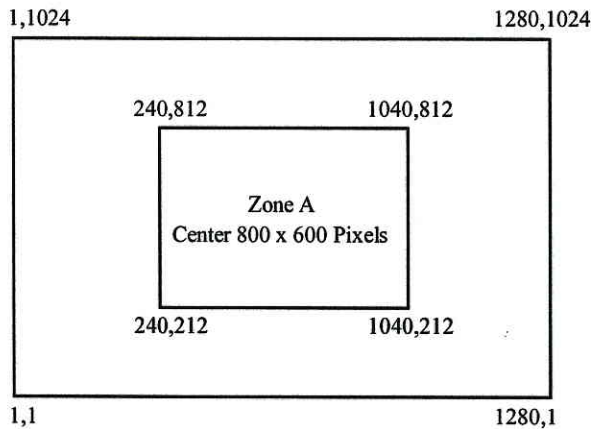


4.3 Cosmetic Specification

Defect tests performed at T=25°C.

Class	Point Defects		Cluster Defects		Column Defects	
	Total	Zone A	Total	Zone A	Total	Zone A
C1	≤5	≤2	0	0	0	0
C2	≤10	≤5	≤4	≤2	0	0
C3	≤20	≤10	≤8	≤4	≤2	0



- Point Defect DARK: A pixel which deviates by more than 6% from neighboring pixels when illuminated to 70% of saturation, OR BRIGHT: A Pixel with dark current > 7500 e/pixel/sec at 25C.
- Cluster Defect A grouping of not more than 5 adjacent point defects
- Column Defect A grouping of >5 contiguous point defects along a single column, OR
A column containing a pixel with dark current > 20,000e/pixel/sec, OR A column that does not meet the minimum vertical CCD charge capacity, OR
A column which loses more than 150e under 2Ke illumination.
- Neighboring pixels The surrounding 128 x 128 pixels or ±64 columns/rows.
- Defect Separation Column and cluster defects are separated by no less than two (2) pixels in any direction (excluding single pixel defects).
- Defect Region Exclusion Defect region excludes the outer two (2) rows and columns at each side/end of the sensor.



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